TENTATIVE

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC9284BF

CD SINGLE CHIP PROCESSOR WITH BUILT-IN 1BIT DA CONVERTER

The TC9284BF is a single chip processor for sync separation protection/synchronization, EFM demodulation, error correction/interpolation, microcomputer interface, CLV servo a focus tracking servo in CD player system. And, built-in 1bit DA converter. In combination with the TA8190F/TA8191F/TA2031F/TA2035F/TA2065F/TA2077F, which are focus tracking servo LSI, a CD player system can be composed very simply.

QFP80-P-1420-0.80A

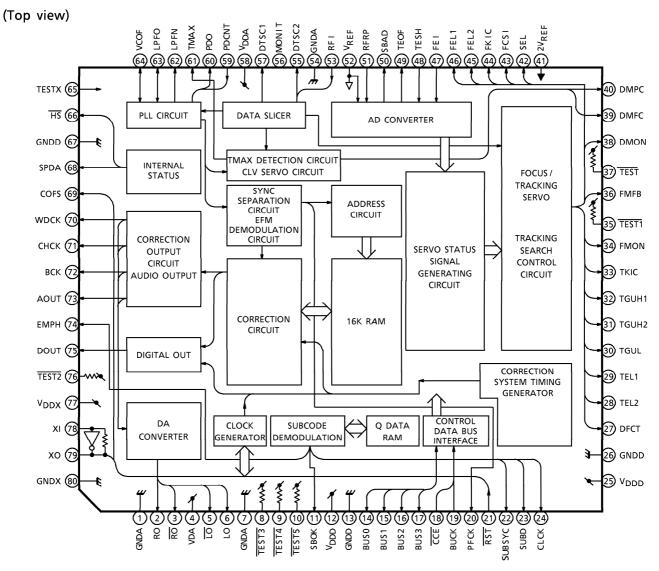
Weight: 1.57g (Typ.)

FEATURES

- Positive sync pattern detection, sync signal protection and synchronization.
- Built-in EFM demodulation and subcode demodulation circuit.
- Has the correction capacity of single and double corrections for C1 and C2 correcting units, respectively, using CIRC correction theoretical format.
- Jitter absorbing capacity of ±5 frames.
- Built-in 16K RAM.
- Built-in digital out circuit.
- Smooth muting through zero cross detection.
- Read timing free subcode Q data.
- Built-in data slicer and analog PLL (free-adjustment VCO adopted) circuit.
- Focus/tracking loop gain auto adjusting function incorporated.
- Built-in AFC and APC circuits for disc motor CLV servo.
- Built-in focus tracking servo control circuit.
- Tracking search control capable of coping with all modes.
- Built-in 1bit DA converter.
 - Function of DA converter.
 - (1) Built-in 8-time oversampling digital filter.
 - (2) Built-in soft mute function.
- Built-in microcomputer interface circuit.
- Double speed play is possible.
- In CMOS structure, high speed and low power dissipation.
- 80 pin flat package.

2001-06-19

PIN CONNECTION/BLOCK DIAGRAM



PIN FUNCTION

PIN No.	SYMBOL	1/0	FUNCTIONAL DESCRIPTION	REMARKS		
1	GNDA	_	Analog grand terminal for DA converter (R channel)	1		
2	RO	0	R channel data forward output terminal.	-		
3	RO	0	R channel data reverse output terminal.	_		
4	V_{DA}	_	Analog power supply terminal for DA converter.	_		
5	ĪŌ	0	L channel data reverse output terminal.	_		
6	LO	0	L channel data forward output terminal.	_		
7	GNDA	_	Analog grand terminal for DA converter (L channel)	_		
8	TEST3	I	Test terminal. Normally, keep at "H" level or open.			
9	TEST4	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor		
10	TEST5	I	Test terminal. Normally, keep at "H" level or open.			
	40 O.K	_	Subcode Q data CRC check adjusting result output			
11	SBOK	0	terminal.	_		
- 10			The adjusting result is OK at "H" level.			
12	V_{DDD}	_	Digital supply voltage terminal. (+5V)	_		
13	GNDD	_	Digital ground terminal.	<u> </u>		
	14 BUS0 / I/O		Command and data sending/receiving input/output	Schmitt input		
			terminals.	Open drain output		
17	BUS3			With pull-up resistor		
		CE I	Command and data sending/receiving chip enable signal			
18	CCE		input terminal.			
			The bus line becomes active at "L" level.	Schmitt input		
19 BUCK		1	Command and data sending / receiving clock input			
	DOCK		terminal.			
20	PFCK	0	Regeneration system frame periodic signal output	_		
20	TTCK		terminal. 7.35kHz	_		
21	RST	1	Reset input terminal.	With pull-up resistor		
۷ ۱		'	The internal system is reset at "L" level.	with pun-up resistor		
22	SUBSYC	0	Subcode sync signal output terminal.	_		
23	SUBD	0	Subcode P~W output terminals.	_		
24	CLCK		Subcode P~W data readout clock input terminal.	l		
25	V_{DDD}	-	Digital supply voltage terminal.	I		
26	GNDD	l	Digital ground terminal.	_		
27	DFCT	0	Defect detection signal output terminal. V _{REF} when			
21	DFCI	O	defect is detected. Normally, HiZ.	_		
28	TEL2	_	Tracking gain adjusting analog switch output terminals			
29	TEL1	0	V _{REF} or HiZ.	_		
			Tracking servo loop low frequency phase compensator			
30	TGUL	0	change-over analog switch output terminal.	_		
			HiZ (gain up) when detecting shock. Normally, V _{REF} .			

PIN FUNCTION

PIN No.	SYMBOL	1/0	FUNCTIONAL DESCRIPTION	REMARKS		
31	TGUH2	0	Tracking servo loop middle/high frequency phase compensator change-over analog switch output terminals.			
32	TGUH1	0	HiZ (gain up) when detecting shock. Normally, V _{REF} . TGUH1 is used at normal regeneration and TGUH2 is used at double speed regeneration.	_		
33	TKIC	0	Tracking actuator kick signal output terminal. Kicks in the outer circumferential direction at "H" level and in the inner circumferential direction at "L" level.	3-state output		
34	FMON	0	Feed servo ON/OFF analog switch output terminals. Servo on at "HiZ". Servo off at "V _{REF} ".	_		
35	TEST1	1	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor		
36	FMFB	0	Feed motor FWD/BWD feeding control signal output terminal. Feed in the outer circumferential direction at "H" level and in the inner circumferential direction at "L" level.	3-state output		
37	TEST	ı	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor		
38	DMON	0	Disc motor driving circuit gain change-over analog switch output terminal.	<u> </u>		
39	DMFC	0	Disc motor CLV servo AFC signal output terminal. COMMAND DMFC OUTPUT OPERATION DMFK H Motor acceleration DMSV PWM CLV servo ON DMBK L Motor deceleration DMOFF VREF CLV servo OFF	3-state output		
40	DMPC	0	Disc motor CLV servo APC signal output terminal.	3-state output		
41	2V _{REF}	ı	Double times reference voltage input terminal. ($V_{REF} \times 2$)	_		
42	SEL	0	SEL LD ON/OFF FOCUS SERVO OPERATION L OFF OFF LD OFF HIZ ON OFF Focus Search H ON ON FOCUS SERVO OPERATION Normal play, etc. Focus Servo ON : FOK)	3-state output		

PIN No.	SYMBOL	1/0		FUNCTIO	ON DESCRIPTION	REMARKS
			Focus actuate focus search	_	ignal output terminal in the	
43	FCSI	0	COMMAND	FCSI OUTPUT	OPERATION	3-state output
"			FORST	Н	Lens gets for away from disc	
			FOSET	L	Lens gets near disc	
			Others	HiZ	Other than focus search	
			Focus actuate focus gain ac	_	ignal output terminal in the ode.	
44	FKIC	0	COMMAND	FKIC OUTPUT	OPERATION	3-state output
44			FGASR	Н	Lens gets for away from disc	3-state output
			FGASS	L	Lens gets near disc	
			Others	HiZ	Other than focus adjustment	
45	FEL2	0	Fucus again	adjusting a	nalog switch output terminals.	
46	FEL1				·	
47	FEI	ı	Focus error s		Analog output	
48	TESH	ı	Tracking erro	_	put sample holding analog	_
49	TEOF	0	output termi	nal.	n ON/OFF analog switch	_
50	SBAD	ı	Sub beam ac	dding signa	l input terminal.	A seal and in most
51	RFRP	ı	RF ripple sig	nal input te	erminal.	Analog input
52	V _{REF}	ı	Reference vo	ltage input	terminal. (+2.1V)	_
53	RFI	I	RF signal inp	ut termina	l.	Analog input
54	GNDA	_	Analog grou	nd termina	l.	_
55	DTSC2	0	Data slice co	ntrol EFM s	signal passive output terminal.	_
56	MONIT	0	Internal signaterminal. Sel		LCK, LOCK and MBOV) output ommand.	_
57	DTSC1	0	Data slice co	ntrol EFM s	signal negative output terminal.	_
58	V_{DDA}	_	Analog supp	ly voltage t	terminal. (+ 5V)	_
59	PDCNT	I	PDO output At "L" level,		minal. ut is made to HiZ by force.	_
60	PDO	0	Phase error s	signal outpo	ut terminal between EFM signal	3-state output

PIN No.	SYMBOL	1/0	FUNCTIONAL DESCRIPTION	REMARKS					
			TMAX signal output terminal. Hiz at time of system clock.						
			TMAX PERIOD TMAX OUTPUT						
61	TMAX	0	Longer than L specified period	3-state output					
			Shorter than H (2V _{REF}) Specified period HiZ						
62	LPFN		LPF amplifier inverting input terminal for PLL.	_					
63	LPFO	0	LPF amplifier output terminal for PLL.	_					
64	VCOF	ı	VCO filter terminal.	_					
65	TESTX	I	Test terminal.	_					
66	НS	0	Double speed monitor output terminal. Double speed operation at "L" level.	_					
67	GNDD	_	Digital ground terminal.	_					
68	SPDA	0	Processor status signal output terminal. Correction process judging result, memory buffer capacity, etc.	_					
69	COFS	0	Correction system frame periodic signal output terminal. 7.35kHz.	_					
70	WDCK	0	Word clock output terminal. Normally, 88.2kHz.	_					
71	снск	0	Channel clock output terminal. Normally, 44.1kHz.	_					
72	вск	0	Bit clock output terminal. Normally, 1.4112MHz.	_					
73	AOUT	0	Audio data output terminal.	_					
74	ЕМРН	0	Emphasis ON/OFF indication signal output terminal. Emphasis ON at "H" level.	_					
75	DOUT	0	Digital out output terminal.	_					
76	TEST2	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor					
77	V_{DDX}	0	Oscillator supply voltage terminal.	_					
78	ΧI	I	Crystal oscillator connecting terminal.						
79	хо	0	crystal oscillator conflecting terminal.	XI XO					
80	GNDX	0	Oscillator grand terminal. —						

MAXIMUM RATINGS ($Ta = 25^{\circ}C$)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Power Supply Voltage	V_{DD}	-0.3~6.0	V
Input Voltage	VIN	-0.3~V _{DD} +0.3	V
Power Dissipation	PD	1250	mW
Operating Temperature	T _{opr}	- 35~85	°C
Storage Temperature	T _{stg}	- 55~150	°C

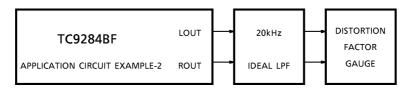
ELECTRICAL CHARACTERISTICS

(Unless otherwise specified, $V_{DD} = 5V$, $2V_{REF} = 4.2V$, $V_{REF} = 2.1V$, Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TES	T CONDITION	MIN.	TYP.	MAX.	UNIT
Operating Supply Voltage		V_{DD}	_	Ta = −35~85°C		4.5	5.0	5.5	V
Operating Supp	oly Current	I _{DD}		XI = 16.9344 In normal			40	70	mA
	"H" Level	V _{IH} (1)		Whole inpu	ut terminals except	3.5	1	$V_{DD} + 0.3$	
Innut Valtaga	"L" Level	V _{IL} (1)		-	UCK and CCE	0	_	1.5	v
Input Voltage	"H" Level	V _{IH} (2)		BUSO~3, B	-	4.0	_	$V_{DD} + 0.3$	· ·
	"L" Level	V _{IL} (2)		(Schmitt in	put)	0	_	1.0	
Input Current	"H" Level	lін	_	VIH — JVI	MOS input terminals cept analog input	_	_	1.0	μΑ
Imput Current	"L" Level	կլ		V _{IL} = 0V te		- 1.0	_	_	μ Λ
Try State Leak	"H" Level	ITLH		V _{IH} = 5V		<u> </u>	_	1.0	μΑ
Current	"L" Level	ITLL		V _{IL} = 0V	V _{IL} = 0V			_	μ –
	"H" Level	I _{OH} (1)		V _{OH} = 4.6V	WDCK, CHCK, BCK, AOUT, DOUT, XO	_	_	- 2.0	
	"L" Level	lOL (1)	_	V _{OL} = 0.4V	V _{OUT} = V _{DD}	2.0	_	_	
	"H" Level	I _{OH} (2)		V _{OH} = 4.6V	SBOK, PFCK, SUBSYC, SUBD, CLCK, SEL, HS, FCSI, FKIC, PDCNT,	_	_	- 0.5	
Output Current	"L" Level	I _{OL} (2)	_	VOL = 0.4V	MONIT, COFS, SPDA VOUT = VDD	1.0	_	_	A
Carrent	"H" Level	IOH (3)		V _{OH} = 3.8V	TKIC, FMFB, DMFC, DMPC, TMAX	_	_	-0.4	mA
	"L" Level	I _{OL} (3)	_	V _{OL} = 0.4V	V _{OUT} = 2V _{REF}	1.0	_	_	
	"H" Level	I _{OH} (4)		V _{OH} = 3.8V	PDO	_	_	- 1.0	
	"L" Level	^I OL (4)	_	V _{OL} = 0.4V	V _{OUT} = 2V _{REF}	1.0	_	_	
Analog Switch	"H" Level	^I OFH		V _{IH} = 5V	1	_	_	1.0	
OFF Current	"L" Level	lOFL	_	V _{IL} = 0V		- 1.0	_	_	μ A

CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Analog Switch ON Resistance	RON (1)	_	FEL1/2, TEL1/2, FMON, TGUL, TGUH1/2, DFCT, TEOF, DMON	l	l	0.3	kΩ
	RON (2)		TESH		-	0.6	
	R _{UP} (1)		RST		50		
Pull-up Resistance	R _{UP} (2)	_	TEST, TEST1~5		30	_	kΩ
	R _{UP} (3)		BUS3~0	8	_	_	
Oscillation Amplifier Feedback Resistance	R _N	_	XI XO between	2	4	6	kΩ
Operating Frequency Ratio	f _{op}		XI	6	_	28	MHz
Total Harmonic Distortion + Noise	THD + N	1	1kHz sine wave Full-scale input	I	- 85	- 80	dB
S/N Ratio	S/N	1		90	98	_	dB
Dynamic Range	DR	1	1kHz sine wave -60dB input conversion	90	95		dB
Cross-talk	СТ	1	1kHz sine wave Full-scale input		- 95	- 85	dB

TEST CIRCUIT 1: Application circuit example-2 is used.



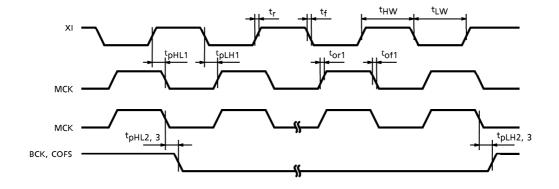
LPF : SHIBASOKU 725C BUILT-IN FILTER
DISTORTION FACTOR GAUGE : SHIBASOKU 725C OR EQUIVALENT

MEASURING ITEM	DISTORTION FACTOR GAUGE FILTER SETTING A WEIGHT
THD + N, CT	OFF
S/N, DR	ON

A WEIGHT : IEC-A OR EQUIVALENT

AC CHARACTERISTICS (1) Clock system timing

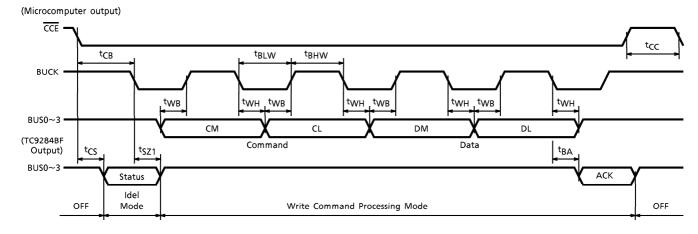
CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Clock Pulse	"H" Level	tHW			18	_	_	
Width	"L" Level	t _{LW}		XI input	18	_	_	
Input Rising Ti	ne	t _r	-		_	_	10	ns
Input Falling Ti	me	t _f			_	_	10	
Transfer Time	"H" Level	t _{pHL1}		XI→MCK	_	_	60	
(1)	"L" Level	t _{pLH1}	1 —		_	_	60	
Transfer Time	"H" Level	t _{pHL2}		MCK→BCK	_	_	60	
(2)	"L" Level	t _{pLH2}			_	_	60	ns
Transfer Time	"H" Level	t _{pHL3}		MCK→COFS	_	_	100	
(3)	"L" Level	t _{pLH3}	_	IVICK-COF3	_	_	100	
Output Rising	Time (1)	t _{or1}		MCV PCV	_	_	15	
Output Falling Time (1)		t _{of1}	1 —	MCK, BCK	_	_	15	ns
Output Rising Time (2)		t _{or2}		COEC	_	_	40	nc
Output Falling	Time (2)	t _{of2}	_	COFS	_	_	40	ns



(2) Microcomputer interface timing

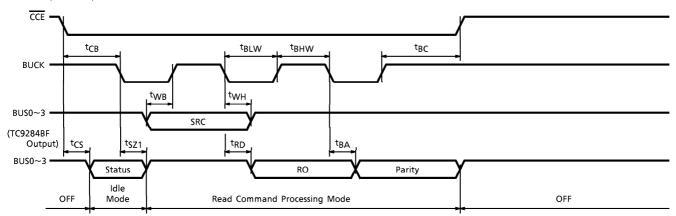
CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Clock Pulse	"H" Level	t _{BHW}		BUCK	10	_	_	
Width (1)	"L" Level	t _{BLW}		BUCK	10	_	_	,,,
Clock Pulse Width (2)	"H" Level	tcc		CCE	6	_	_	μ s
Delay Time (1)		t _{CB}	-	<u>CCE</u> →BUCK	l	_	6	
Delay Time (2)		t _{WB}	1	Command Data→BUCK	0	_	_	
Delay Time (3)		t _{CS}	1	CCE→Status Output	l	_	6	μ s
Delay Time (4)		t _{BC}	_	BUCK→CCE	6	_	_	
Setup Time (1)		t _{RD}	_	BUCK→Read Data Output	_	_	6	
Setup Time (2)		t _{BA}	_	BUCK→ACK, Each Parity Output	-	_	6	μ s
Hold time (1)		t _{SZ1}	_	BUCK→Status, ACK, Each Parity Output	_	_	6	
Hold time (2)		t _{SZ2}	_	CCE→Status Output		_	6	μ s
Hold time (3)		tWH	_	BUCK→Command Data	6	_	_	

(a) Write command processing mode



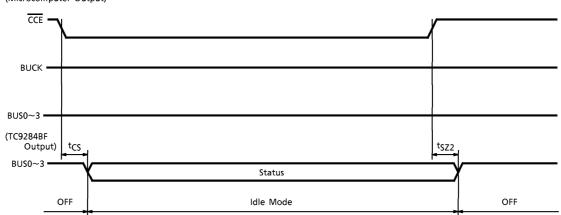
(b) Read command processing mode

(Microcomputer Output)



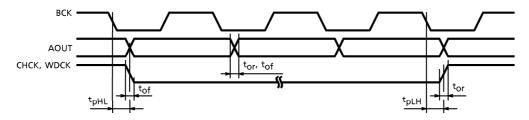
(c) Idle mode

(Microcomputer Output)



(3) Data output timing

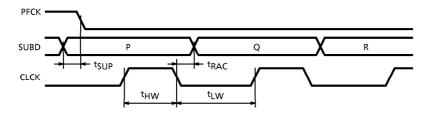
CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t _{pHL}	_	BCK→AOUT, WDCK, CHCK	_	_	30	20
Transfer Time	"L" Level	t _{pLH}	_	BCK—AOUT, WDCK, CHCK	_	_	30	ns
Output Rising Time		tor	_	AOUT, WDCK, CHCK	_	_	15	200
Output Falling	Time	t _{of}	_	AGGI, WEEK, CHEK	_	_	15	ns



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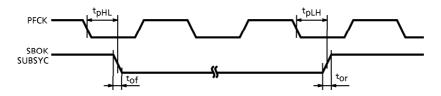
(4) Output timing for subcode P~W

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Clock Pulse	"H" Level	tHW	—	CLCK	2	_	_	
Width	"L" Level	tLW	_	CLCK	2	_	_	μ s
Setup Time		tsup	_	PFCK→SUBD	0.4	_	_	c
Read Access Time		tRAC		CLCK→SUBD	1.2	_		μ s



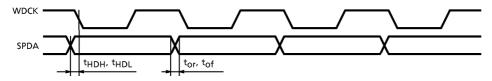
(5) Output timing for subcode Q

	~							
CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t _{pHL}	_	PFCK→SBOK, SUBSYC	- 50	_	200	ns
	"L" Level	t _{pLH}	_		- 50	_	200	
Output Rising Time		tor	_	SBOK, SUBSYC		_	40	ns
Output Falling Time		t _{of}	_		_	_	40	



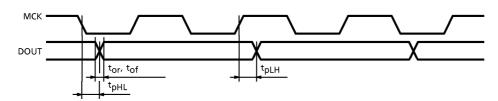
(6) Status signal output timing

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Hold Time	"H" Level	tHDH	_	WDCK→SPDA	_	_	200	ns
	"L" Level	tHDL	_		_	_	200	
Output Rising Time		tor	_	·SPDA	_	_	40	ns
Output Falling Time		t _{of}	_		_	-	40	

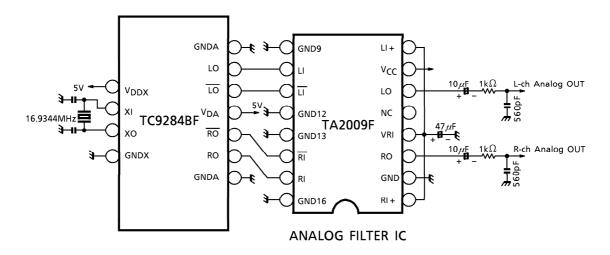


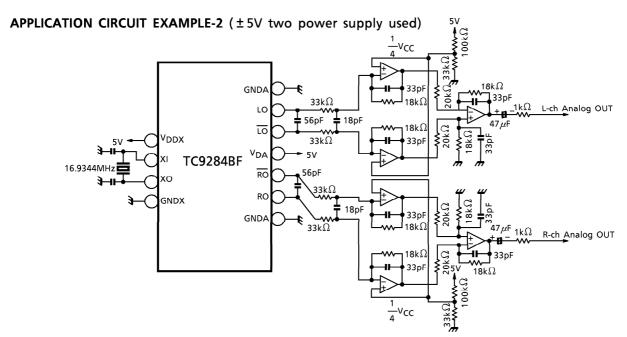
(7) Digital out output timing

CHARACTERISTIC		SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t _{pHL}	_	MCK→DOUT	_		60	20
	"L" Level	t _{pLH}	_		_	_	60	ns
Output Rising Time		tor	_	DOUT	_	_	14	nc
Output Falling Time		tof	_		_	_	14	ns



APPLICATION CIRCUIT EXAMPLE-1 (+5V single power supply used)



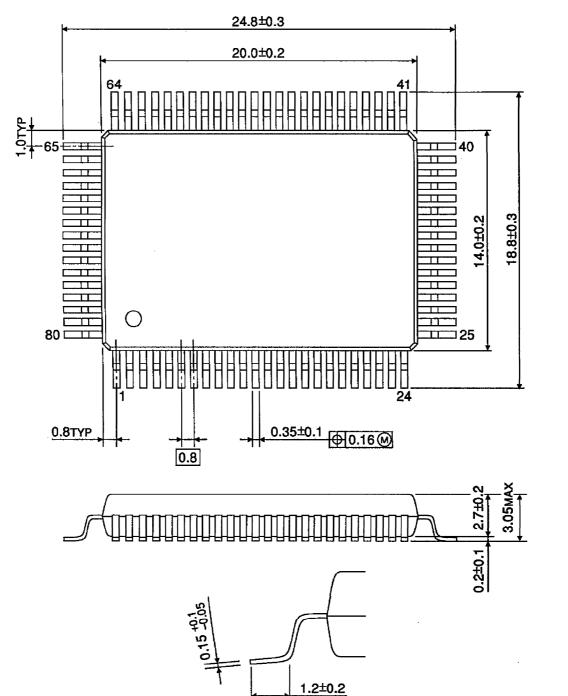


(Cautions)

- Quality of crystal oscillation wave form largely affect S/N ratio and noise distortion. Further, this is also true then system clock is input externally through the XI terminal.
- The wiring between the TC9284BF output and the TA2009F input must be made the shortest.
- The condenser between V_{DD} and GND shall be connected as close to the pin as possible.

PACKAGE DIMENSIONS

QFP80-P-1420-0.80A Unit: mm



Weight: 1.57g (Typ.)

RESTRICTIONS ON PRODUCT USE

000707EBA

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